Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/798,649	LEE ET AL.	
Examiner	Art Unit	
David J. Walczak	3751	

SEARCHED					
Class	Subclass	Date	Examiner		
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INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
401	128, 132,	6/27/2006	DW			
	134, 41					
206	219					

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
TE	EXMR			
/2006	DW			